

INFORMATION DISCLOSURE STATEMENT

Pursuant to MPEP § 609, Applicants understand that the Examiner will, as part of his examination of this application, consider the art of record in the parent application (and the grandparent application). A form PTO-1449 is enclosed, citing, inter alia, the art of record in the parent application, but, pursuant to MPEP § 609, no copies of such art are provided; should the Examiner wish to have such submitted, however, Applicants will gladly do so upon request.

English translations and/or English Abstracts of at least some of the listed non-English documents were of record in the parent application, and the Examiner is respectfully referred to those translations/Abstracts with regard to relevance for the corresponding non-English documents.

Applicants also direct the Examiner's attention to the Office Actions (dated March 18, 2003 and September 8, 2003) issued in related Application No. 10/235,811. One copy of each Office Action is attached.

U.S. Patent 6,169,356 issued from U.S. Application No. 08/264,497, of record in the parent application.

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 03500.011080.9		APPLICATION NO. NYA	
				APPLICANT YOSHIKAZU BANNO ET AL.			
				FILING DATE FILED HEREWITH			GROUP 1734
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		3,611,077	10/71	Smith	315	94	
		5,023,110	6/91	Nomura et al.	427	49	
		5,650,199	7/97	Chang et al.	427	333	
		5,320,703	6/94	Ikeda	117	68	
		4,566,186	4/96	Bauer et al.	29	852	
		4,668,533	5/87	Miller	427	98	
		4,891,242	1/90	Ito et al.	427	53.1	
		5,114,744	5/92	Cloutier et al.	427	96	
		5,275,646	1/94	Marshall et al.	106	20B	
		5,401,535	3/95	Bishop	427	229	
		5,832,595	11/98	Maruyama et al.	29	829	
		5,861,227	1/99	Ikeda et al.	430	31	
		5,505,777	4/96	Ciardella	118	663	
		5,498,444	3/96	Hayes	427	162	
		4,600,137	4/96	Comerford	228	162	
		5,593,499	1/97	Stans	118	63	
		6,169,356	1/01	Ohnishi et al.	313	495	
		5,569,974	10/96	Morikawa et al.	313	310	
		5,066,883	11/91	Yoshioka et al.	313	309	
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,627,111	5/97	Tsukamoto et al.	438	20	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		0620581A	10/94	EPO			
		0658916A2	8/88	EPO			
		JP0256822	2/90	Japan			
		2-247939	10/90	Japan			
		64-5095	1/89	Japan			
		62-181490	8/87	Japan			
		63-200041	8/87	Japan			
		64-64290	8/88	Japan			
		1-296532	11/89	Japan			
		4-121702	8/88	Japan			
		JP 63-200041	8/88	Japan			
		2,013,233	9/90	Canada			English
		EP 0 394 698	10/90	EPO			
		JP 3-55738	3/91	JAPAN			Abstract
EXAMINER				DATE CONSIDERED			

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,511,545	1/03	Banno et al.	118	688	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		JP 63-200041	8/88	Japan			
OTHER DOCUMENT(S) <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
		Patent Abstracts of Japan, Vol. 014, No. 573 (E-1015), December 19, 1990 & JP 02 247939 A (CANON INC.) October 3, 1990					
		H. Araki et al., "Electroforming and Electron Emission of Carbon Thin Films", J. Vac. Soc. Jpn., 26, 1, 22-29 (1981)					
		M. Hartwell et al., "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films", Int'l Electron Devices Mtg., Washington, D.C., 519-21 (1975)					
		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", Thin Solid Films, 9, 317-28 (1972)					
		W. Dyke et al., "Field Emission", Advances in Electronics and Electron Phys., 89-185 (1956)					
		M. Elinson et al., "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide", Radio Eng'g and Electronic Phys., 1290-96 (1965).					
		C. Mead, "Operation of Tunnel-Emission Devices", J. App. Phys., 32(4), 646-52 (1961).					
		C. Spindt et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cone," J. App. Phys., 47(12), 5240-63 (1976).					
EXAMINER				DATE CONSIDERED			

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